

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Ryszard Sprycha et al.
Application No. : 10/522,972 Confirmation No.: 4612
Filed : March 21, 2008
For : APPARATUS AND METHOD FOR
QUANTITATIVELY MEASURING LIQUID FILM
DRYING RATES ON SUBSTRATES
Group Art Unit : 2856
Examiner : Kolb, Nathaniel J.
Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

RESPONSE TO *EX PARTE QUAYLE* ACTION

Sir:

This is in response to the Office Action mailed June 24, 2010 ("*Ex parte Quayle* Action") in connection with the above-identified application. A shortened statutory period for a response to the *Ex parte Quayle* Action was set to expire two months or thirty days, whichever is longer, from the mailing date of the Office Action, and therefore, was due on August 24, 2010. This Response to *Ex parte Quayle* Action is being filed with a one-month extension of time together with the required extension fee, thereby setting the due date to September 24, 2010. Accordingly, this Response to *Ex parte Quayle* Action is being timely filed.

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 4 of this paper.